Applicant(s)/Patent Under Application/Control No. Reexamination 10/807,462 DEWAN ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2876 Daniel St.Cyr **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY 340/010.51 02-2006 Kean et al. US-2006/0028319 Α US-В US-С US-D US-Ε US-F G US-Н US-US-US-US-K US-US-М FOREIGN PATENT DOCUMENTS Date **Document Number** Classification Name Country Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W Х

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